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- B-Port Outputs Have Equivalent 25-Ω Series Resistors, So No External Resistors Are Required
- State-of-the-Art *EPIC-*II*B*[™] BiCMOS Design Significantly Reduces Power Dissipation
- Latch-Up Performance Exceeds 500 mA Per JEDEC Standard JESD-17
- ESD Protection Exceeds 2000 V Per MIL-STD-833, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)
- Typical V_{OLP} (Output Ground Bounce) < 1 V at V_{CC} = 5 V, T_A = 25°C
- High-Impedance State During Power Up and Power Down
- Package Options Include Plastic Small-Outline (DW), Shrink Small-Outline (DB), and Thin Shrink Small-Outline (PW) Packages, Ceramic Chip Carriers (FK), Plastic (N) and Ceramic (J) DIPs, and Ceramic Flat (W) Package

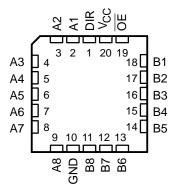
description

These octal transceivers and line drivers are designed for asynchronous communication between data buses. The devices transmit data from the A bus to the B bus or from the B bus to the A bus, depending on the logic level at the direction-control (DIR) input. The output-enable (\overline{OE}) input can be used to disable the device so the buses are effectively isolated.

SN54ABT2	SN54ABT2245 J OR W PACKAGE SN74ABT2245 DB, DW, N, OR PW PACKAGE					
SN74ABT2245	. DB, DW, N, OR PW PACKAGE					
	(TOP VIEW)					

	(••=••,	
DIR [1	O_{20}	Vcc
A1 [2	19] OE
A2 [3	18] B1
A3 [4	17] B2
A4 [5	16] B3
A5 [6	15] B4
A6 [7	14] B5
A7 [8	13] B6
A8 [9	12] B7
GND [10	11] B8

SN54ABT2245 . . . FK PACKAGE (TOP VIEW)



The B-port outputs, which are designed to sink up to 12 mA, include equivalent $25-\Omega$ series resistors to reduce overshoot and undershoot.

When V_{CC} is between 0 and 2.1 V, the device is in the high-impedance state during power up or power down. However, to ensure the high-impedance state above 2.1 V, \overline{OE} should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking/current-sourcing capability of the driver.

The SN54ABT2245 is characterized for operation over the full military temperature range of –55°C to 125°C. The SN74ABT2245 is characterized for operation from –40°C to 85°C.

FUNCTION TABLE							
INP	UTS	OPERATION					
OE	DIR	OPERATION					
L	L	B data to A bus					
L	Н	A data to B bus					
Н	Х	Isolation					



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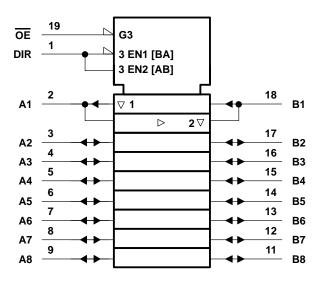
PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.



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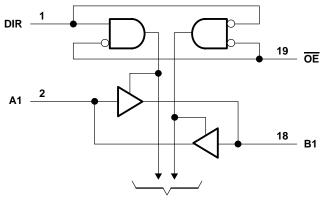
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logic symbol[†]



[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

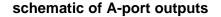
logic diagram (positive logic)

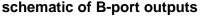


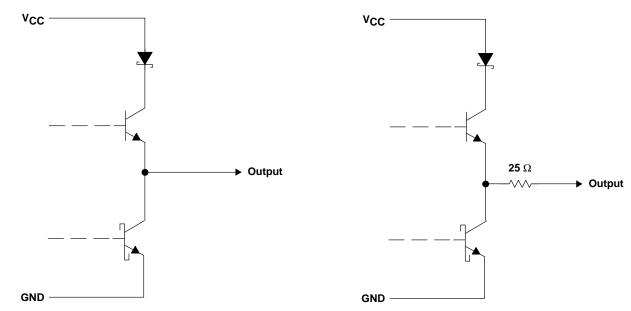
To Seven Other Channels



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All resistor values shown are nominal.

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range, V _{CC} Input voltage range, V _I (except I/O ports) (see N		
Voltage range applied to any output in the high	or power-off state, VO	
Current into any output in the low state, IO: SN	54ABT2245 (except B port)	96 mA
SN	74ABT2245 (except B port)	128 mA
Input clamp current, IIK (VI < 0)		
Output clamp current, I _{OK} (V _O < 0)		
Package thermal impedance, θ_{JA} (see Note 2):		
	DW package	
	N package	
	PW package	128°C/W
Storage temperature range, T _{stg}		

⁺ Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output negative-voltage ratings may be exceeded if the input and output clamp-current ratings are observed.

2. The package thermal impedance is calculated in accordance with EIA/JEDEC Std JESD51, except for through-hole packages, which use a trace length of zero.



SN54ABT2245, SN74ABT2245 OCTAL TRANSCEIVERS AND LINE/MOS DRIVERS WITH 3-STATE OUTPUTS SCBS234D – SEPTEMBER 1992 – REVISED MAY 1997

recommended operating conditions (see Note 3)

		SN54AE	ST2245	SN74AB	UNIT			
			MIN	MAX	MIN	MAX	UNIT	
V _{CC} Supply voltage				5.5	4.5	5.5	V	
VIH	High-level input voltage		2		2		V	
VIL	Low-level input voltage			0.8		0.8	V	
VI	Input voltage		0	VCC	0	VCC	V	
lau	High lovel output ourrest	A port		-24	-32	mA		
ЮН	OH High-level output current	B port		-12		-12	mA	
le:		A port		48		64	mA	
IOL	Low-level output current	B port		12		12	mA	
$\Delta t / \Delta v$	Input transition rise or fall rate	Outputs enabled		5		5	ns/V	
Δt/ΔV _{CC}	Power-up ramp rate		200		200		μs/V	
Тд	T _A Operating free-air temperature			125	-40	85	°C	

NOTE 3: Unused pins (input or I/O) must be held high or low to prevent them from floating.



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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

		TEST CONDITIONS		т	A = 25°C	:	SN54AB	T2245	SN74ABT2245		LINUT	
PARAMETER		TEST CON	TEST CONDITIONS			MIN TYP [†] MAX			MIN	MAX	UNIT	
VIK		V _{CC} = 4.5 V,	lı = –18 mA			-1.2		-1.2		-1.2	V	
		V _{CC} = 4.5 V,	I _{OH} = –1 mA	3.35			3.3		3.35			
	Draat	V _{CC} = 5 V,	I _{OH} = –1 mA	3.85			3.8		3.85			
	B port		I _{OH} = -3 mA				3		3.1			
		V _{CC} = 4.5 V	I _{OH} = -12 mA	2.6					2.6		V	
VOH		V _{CC} = 4.5 V,	I _{OH} = -3 mA	2.5			2.5		2.5		V	
	Anort	V _{CC} = 5 V,	IOH = -3 mA	3			3		3			
	A port	V _{CC} = 4.5 V	I _{OH} = -24 mA	2			2					
		VCC = 4.5 V	I _{OH} = -32 mA	2*					2			
	P. port		I _{OL} = 8 mA			0.65		0.8		0.65		
Va	B port		I _{OL} = 12 mA			0.8				0.8	v	
VOL	A port	V _{CC} = 4.5 V	I _{OL} = 48 mA			0.55		0.55			v	
	A port		I _{OL} = 64 mA			0.55*				0.55		
V _{hys}					100						mV	
	Control inputs	$V_{CC} = 0$ to 5.5 V, V _I =	· V _{CC} or GND			±1		±1		±1		
I	A or B ports	$V_{CC} = 2.1 \text{ V to } 5.5 \text{ V},$ $V_{I} = V_{CC} \text{ or GND}$				±20	±20			±20	μA	
I _{OZH} ‡		$V_{CC} = 2.1 \text{ V} \text{ to } 5.5 \text{ V},$ $V_{O} = 2.7 \text{ V}, \text{ OE} \ge 2 \text{ V}$				10		10		10	μA	
$V_{CC} = 2.1 \text{ V to } 5.5 \text{ V},$ $V_{O} = 0.5 \text{ V}, \overline{OE} \ge 2 \text{ V}$					-10		-10		-10	μA		
IOZPU [§]		$V_{CC} = 0 \text{ to } 2.1 \text{ V},$ $V_{O} = 0.5 \text{ V to } 2.7 \text{ V}, \overline{\text{OE}} = \text{X}$				±50		±50		±50	μA	
IOZPD	ŝ	$V_{CC} = 2.1 \text{ V to 0},$ $V_{O} = 0.5 \text{ V to 2.7 V}, \overline{\text{OE}} = X$				±50		±50		±50	μA	
loff		V _{CC} = 0,	V_{I} or $V_{O} \le 4.5 V$			±100				±100	μA	
ICEX	Outputs high	V _{CC} = 5.5 V,	V _O = 5.5 V			50		50		50	μΑ	
	B port			-25		-100	-25	-100	-25	-100		
ю¶	A port	V _{CC} = 5.5 V,	VO =25.7 v	-50	-100	-180	-50	-180	-50	-180	mA	
	1	V _{CC} = 5.5 V,	Outputs high		1	250		250		250	μA	
ICC	A or B ports	I _O = 0,	Outputs low		24	32		32		32	mA	
		$V_{I} = V_{CC}$ or GND	Outputs disabled		0.5	250		250		250	μA	
∆I _{CC} #	Data inputs	Ono ir	/ _{CC} = 5.5 V, Dne input at 3.4 V,	Outputs enabled			1.5		1.5		1.5	
		Other inputs at V _{CC} or GND	Outputs disabled			0.05		0.05		0.05	mA	
	Control inputs	$V_{CC} = 5.5$ V, One input at 3.4 V, Other inputs at V _{CC} or GND				1.5		1.5		1.5		
Ci		V _I = 2.5 V or 0.5 V 3			pF							
C _{io}		V _O = 2.5 V or 0.5 V			6						pF	

* On products compliant to MIL-PRF-38535, this parameter does not apply.

[†] All typical values are at V_{CC} = 5 V.

 \ddagger The parameters I_{OZH} and I_{OZL} include the input leakage current.

§ This parameter is characterized but not production tested.

¶ Not more than one output should be tested at a time, and the duration of the test should not exceed one second.

[#]This is the increase in supply current for each input that is at the specified TTL voltage level rather than V_{CC} or GND.



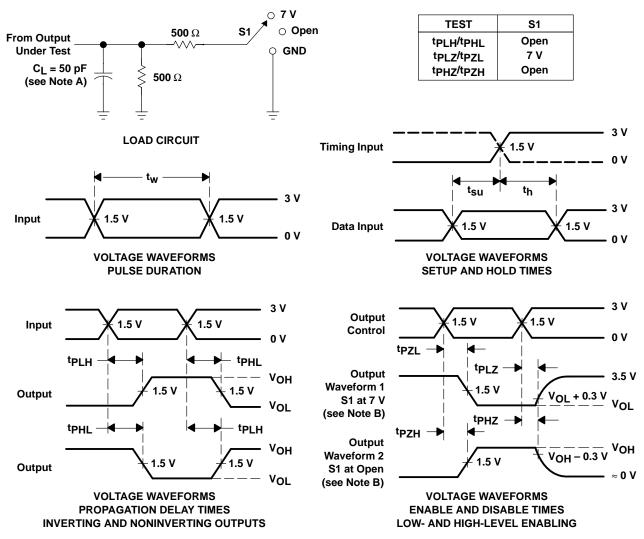
SN54ABT2245, SN74ABT2245 **OCTAL TRANŚCEIVERS AND LINE/MOS DRIVERS** WITH 3-STATE OUTPUTS SCBS234D – SEPTEMBER 1992 – REVISED MAY 1997

switching characteristics over recommended ranges of supply voltage and operating free-air temperature, $C_L = 50 \text{ pF}$ (unless otherwise noted) (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 5 V, T _A = 25°C			SN54ABT2245		SN74ABT2245		UNIT
	(INFOT)	(001-01)	MIN	TYP	MAX	MIN	MAX	MIN	MAX	
^t PLH	А	В	1	2.5	3.4	1	4	1	3.8	ns
^t PHL	A	В	1	3.2	4.2	1	4.6	1	4.5	115
^t PLH	В	А	1	2.2	3.2	1	3.8	1	3.6	ns
^t PHL	В	A	1	2.7	3.6	1	4.2	1	4	115
^t PZH		А	1	3.3	4.6	1	5.6	1	5.5	ns
^t PZL	OE	A	1	3.2	4.7	1	6	1	5.7	115
^t PHZ	OE	А	2	4	5.1	2	5.7	2	5.6	20
^t PLZ	UE	A	1	2.9	4	1	4.6	1	4.5	ns
^t PZH		D	1.5	3.6	4.9	1.5	6.3	1.5	6.1	
^t PZL	OE	В	1.5	3.9	5.3	1.5	6.6	1.5	6.3	ns
^t PHZ	OE	P	1.5	3.6	4.7	1.5	5.5	1.5	5.3	
^t PLZ		В	1.5	3.3	4.4	1.5	4.9	1.5	4.8	ns



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PARAMETER MEASUREMENT INFORMATION

NOTES: A. CL includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control. C. All input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, Z_O = 50 Ω , t_r \leq 2.5 ns, t_f \leq 2.5 ns.

D. The outputs are measured one at a time with one transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms



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